

VAN DER PAUWECOPIAHMS-3000 HALL MEASUREMENT SYSTEM

Equipment Picture:



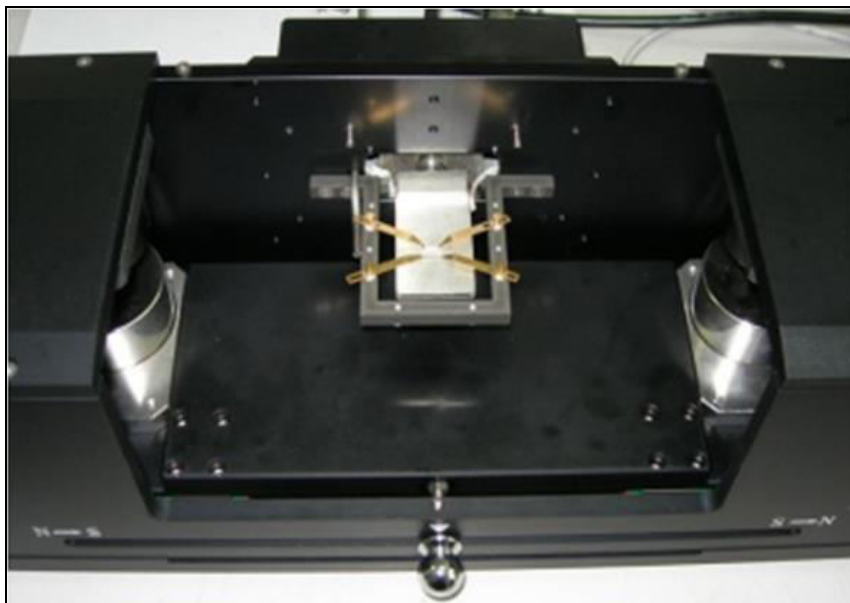
Description of the facility

The HMS-3000 Hall Effect Measurement Systems plot concentration versus temperature, mobility versus temperature, resistivity versus temperature, conductivity versus temperature, and Hall coefficient versus temperature. The systems provides the test results as tabular data as well as in graph form. Once the test is finished, the temperature dependent graphs and tabular data are ready for viewing.

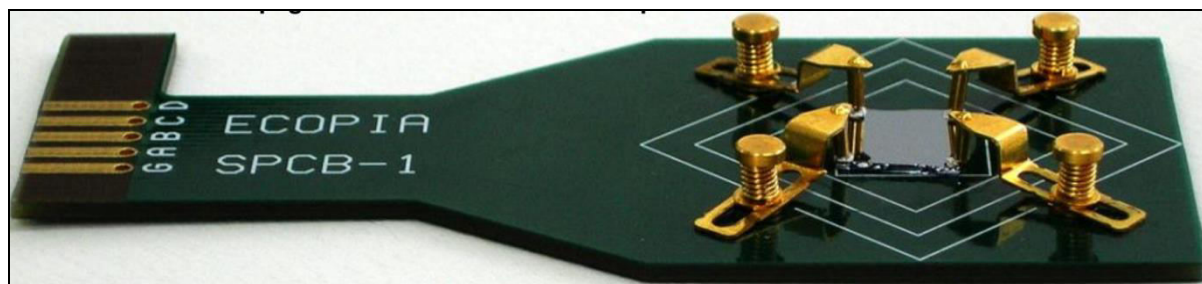
The systems ramp to each user defined temperature, stabilize, makes the measurement (including moving the magnet automatically), and then plots the various temperature dependent material electrical properties.

The HMS-3000 includes software with I-V curve capability for checking the ohmic integrity of the user made sample contacts. The systems can be used to characterize various materials including semiconductors and compound semiconductors (N Type & P Type) such as Si, Ge, SiGe, SiC, GaAs, InGaAs, InP, GaN, ZnO, TCOs, metals, etc., at both 300K and 77K (room temperature and liquid nitrogen temperature).

Picture of the samples



ITO sample mounted on the system



Si mounted on SPIB Board